

Delays

In experiments involving several sources of analog and logic signals, the signals from different paths usually must be aligned to arrive simultaneously at the decision points. This is the function of delay modules. For analog signals the pulse amplitude information must be preserved. Consequently, coaxial cables or lumped-parameter delay lines are used to generate the delay.

With logic pulses, three methods can be used. For short delays, coaxial cables can be employed. A more compact solution uses lumped-parameter delays with logic gates acting as buffers between the many delay sections. These first two solutions minimize the dead time following each pulse. If dead time is not a problem, the simplest method of achieving long delays with logic pulses is to use a “gate and delay generator.” In this case, the original logic signal triggers a “one-shot” circuit. The width of the one-shot pulse sets the delay, and the trailing edge of the one-shot signal triggers the output pulse. Typically, another one-shot is used to set the width of the output pulse.

Logic Modules

In coincidence measurements, logic signals from various parts of the experiment must often be combined to determine which events are to be accepted for analysis. Logic modules provide a flexible means of making these decisions.

Linear Gates

When some analog signals must be blocked, and some must be selected to pass on to a subsequent instrument, a linear gate is required. Linear gates usually provide a variety of ways to use a logic pulse in blocking or passing the analog signal.

Delay Selection Guide

	DB463 Delay Box	425A Nanosecond Delay
Type of Signal	Analog or logic	Analog or logic
Number of Duplicate Channels	4	1
Delay Range per Channel	0 to 63.5 ns	2 to 65 ns
Minimum Delay Adjustment	0.5 ns	1 ns

Gate and Delay Generator Selection Guide

	GG8020 Octal Gate and Delay Generator	416A Gate and Delay Generator
Number of Duplicate Channels	8	1
Module Width	NIM-1	NIM-1
Input	Fast negative NIM logic pulse	Slow positive NIM, or fast negative NIM logic pulse
Outputs	Fast negative NIM and TTL logic pulses	Positive and negative delayed outputs with amplitude adjustable from 2 to 10 V; delay period (+5 V); delay marker (fast negative NIM)
Output Delay	<70 ns to >10 μ s	100 ns to 110 μ s
Output Width	<70 ns to >10 μ s	400 ns to 4 μ s

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Logic Module Selection Guide

	CO4020 Quad 4-Input Logic Unit	414A Fast Coincidence	418A Universal Coincidence
Number of Duplicate Channels	4	1	1
Module Width	NIM-1	NIM-2	NIM-1
Logic Functions	AND, OR	AND, anti-coincidence	Majority AND, NAND
Number of Inputs Per Channel	4	3	5
Input Level	Fast negative NIM negative NIM	Slow positive NIM	Slow positive NIM
Outputs	TTL and Fast	Slow positive NIM	Slow positive NIM
Special Features	Adjustable output widths	Adjustable resolving time widths	Majority logic

Linear Gate Selection Guide

	426 Linear Gate	542 Linear Gate and Stretcher
Input Pulse Amplitude Range	+200 mV to +10 V	+100 mV to +10 V
Minimum and Maximum Rise Time	<0.3 μ s to dc	0.1 to 10 μ s
Input Coupling	ac-coupled with passive, symmetric BLR; can be dc-coupled	dc-coupled, or ac-coupled with active BLR
Output Reshaping	None	Input peak amplitude stretched and gated out as a rectangular output pulse
Gating Functions	Pulse pass, pulse inhibit, dc inhibit	Normally open, coincidence, anticoincidence, external strobe

Specifications subject to change
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